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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re: the application of:

Charles W. Extrand

Attorney Docket No.: 2267.962US01

Confirmation No.: 5391

Application No.: 10/824,340

Filed: April 14, 2004

Group Art Unit: 1724

For: ULTRALYOPHOBIC MEMBRANE

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
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Sir:

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This information is being filed before the mailing date of a first Office Action on the merits. No certification or fee is required.

This application was filed after June 30, 2003; therefore, copies of cited U.S. patents and U.S. published applications are not included.

Respectfully submitted,



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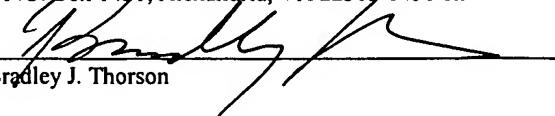
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Bradley J. Thorson

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Complete if Known	
Application Number	10/824,340
Filing Date	April 14, 2004
First Named Inventor	Charles W. Extrand
Art Unit	1724
Examiner Name	

AUG 01 2005

O 1 INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(use as many sheets as necessary)PATENT TRADEMARK OFFICE
SHEET 1 OF 1

of

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Attorney Docket Number

2267.962US01

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EXAMINER INITIAL*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
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		KIYOHARU TADANAGA et al., <u>Super-Water-Repellent Al₂O₃ Coating Films with High Transparency</u> , <i>Communications of the American Ceramic Society</i> , 1997, vol. 80, no. 4, pp. 1040-1042	
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		BRIAN D. REISS et al., <u>DNA-Directed Assembly of Anisotropic Nanoparticles on Lithographically Defined Surfaces and in Solution</u> , <i>Materials Research Society</i> , 2001, vol. 635, pp.C6.2.1-C6.2.6			
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		WEI JIN et al., <u>Wetting Hysteresis at the Molecular Scale</u> , <i>Physical Review Letters</i> , February 24, 1997, vol. 78, no. 8, pp. 1520-1523			
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EXAMINER SIGNATURE				DATE CONSIDERED	
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.</p> <p>This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 120 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.</p>					
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